

Application/Control No.	Applicant(s)/Patent under Reexamination
10/626,693	MEYER, JOHN F.
Examiner	Art Unit
Madeleine AV Nguven	2625

	SEARCHED				
Class	Subclass	Date	Examiner		
update		4/5/2007	AV		
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INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
		DATE	EXMR	
East		4/5/2007	AV	
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